OVP and EMI Protected, Precision, Low Noise and Low Bias Current Op Amp

Data Sheet

ADA4177-2CHIPS

FEATURES

Low offset voltage: 120 µV maximum at 25°C
Low input bias current: 1 nA maximum at 25°C
Low voltage noise density: 8 nV/√Hz typical at 1 kHz
Large signal voltage gain (A_{VO}): 108 dB minimum over full supply voltage and operating temperature
Input overvoltage protection to 32 V above and below the supply voltage rail
Integrated EMI filter
    70 dB typical rejection at 1000 MHz
    90 dB typical rejection at 2400 MHz
Rail-to-rail output swing
Low supply current: 500 µA typical per amplifier
Wide bandwidth
    Gain bandwidth product ($A_V = 100$): 3.5 MHz typical
    Unity-gain crossover ($A_V = 1$): 3.5 MHz typical
    −3 dB bandwidth ($A_V = 1$): 6 MHz typical
Dual-supply operation
    Specified at ±5 V to ±15 V, operates over ±2.5 V to ±18 V
Unity-gain stable
No phase reversal

APPLICATIONS

Wireless base station control circuits
Optical network control circuits
Instrumentation
Sensors and controls
    Thermocouples, RTDs, strain gages, shunt current measurements

GENERAL DESCRIPTION

The ADA4177-2CHIPS is a dual-channel amplifier that features low offset voltage (3 µV typical), low input bias current, low noise, and low current consumption (500 µA typical). Outputs are stable with capacitive loads of more than 1000 pF with no external compensation.

The inputs of the ADA4177-2CHIPS feature outstanding precision amplifier robustness, providing input protection against
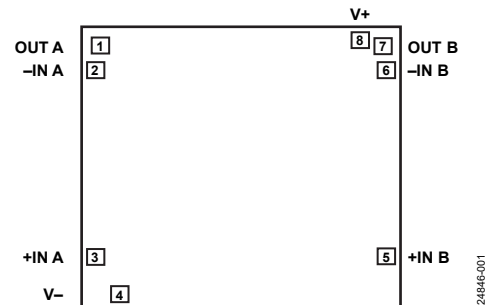
FUNCTIONAL BLOCK DIAGRAM

Figure 1.

signal excursions 32 V beyond either supply, as well as 70 dB of rejection for electromagnetic interference (EMI) at 1000 MHz.

Additional application and technical information can be found in the ADA4177-2 data sheet.

The ADA4177-2CHIPS is specified for +25°C only, and is functional over the −40°C to +125°C temperature range. The ADA4177-2CHIPS is guaranteed only on the specifications of this data sheet.

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REVISION HISTORY

10/2020—Revision 0: Initial Version

SPECIFICATIONS

ELECTRICAL CHARACTERISTICS, ±5 V

Power supply voltage (V_{SY}) = ±5.0 V, common-mode voltage (V_{CM}) = 0 V, T_A = 25°C, unless otherwise noted.

Table 1.

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
INPUT CHARACTERISTICS						
Offset Voltage	V_{OS}			3	120	µV
Offset Voltage Matching					110	µV
Input Bias Current	I_B		−1	−0.4	+1	nA
Input Offset Current	I_{OS}		−0.75	+0.1	+0.75	nA
Input Voltage Range	IVR		−3.5		+3.5	V
Overvoltage Current Limit[1]	I_{OVP}	5 V < V_{CM} < 37 V		12		mA
		−37 V < V_{CM} < −5 V		10		mA
Common-Mode Rejection Ratio	CMRR	−3.5 V ≤ V_{CM} ≤ +3.5 V	122	130		dB
Large Signal (Open-Loop) Voltage Gain	A_{VO}	Load resistance (R_L) = 2 kΩ, output voltage (V_{OUT}) = −4.5 V to +4.5 V	108	110		dB
		R_L = 10 kΩ, V_{OUT} = −4.5 V to +4.5 V	115	120		dB
Input Capacitance	C_{INDM}	Differential mode		1		pF
	C_{INCM}	Common mode		8		pF
Input Resistance	R_{DIFF}	Differential mode		4		MΩ
	R_{CM}	Common mode		100		GΩ
OUTPUT CHARACTERISTICS						
Output Voltage						
High	V_{OH}	Load current (I_{LOAD}) = 1 mA	4.95			V
		I_{LOAD} = 7 mA	4.80			V
Low	V_{OL}	I_{LOAD} = 1 mA			−4.95	V
		I_{LOAD} = 7 mA			−4.80	V
Output Current	I_{OUT}	Dropout voltage ($V_{DROPOUT}$) < 1 V		25		mA
Short-Circuit Current	I_{SC}	T_A = 25°C				
Sourcing				36		mA
Sinking				48		mA
Closed-Loop Output Impedance	Z_{OUT}	f = 1 kHz, closed-loop gain (A_V) = 1		0.11		Ω
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	V_{SY} = ±2.5 V to ±18 V	125	145		dB
Supply Current per Amplifier	I_{SY}	V_{OUT} = 0 V		500	560	µA
DYNAMIC PERFORMANCE						
Slew Rate	SR	R_L = 2 kΩ		1.5		V/µs
Settling Time	t_S					
To 0.1%		Input voltage (V_{IN}) = 1 V step, R_L = 2 kΩ, A_V = −1		1.8		µs
To 0.01%		V_{IN} = 1 V step, R_L = 2 kΩ, A_V = −1		3.5		µs
Gain Bandwidth Product	GBP	V_{IN} = 10 mV p-p, R_L = 2 kΩ, A_V = 100		3.5		MHz
Unity-Gain Crossover	UGC	V_{IN} = 10 mV p-p, R_L = 2 kΩ, A_V = 1		3.5		MHz
−3 dB Closed-Loop Bandwidth	$f_{−3 dB}$	V_{IN} = 10 mV p-p, R_L = 2 kΩ, A_V = 1		6		MHz
Total Harmonic Distortion Plus Noise	THD + N	V_{IN} = 1 V rms, R_L = 2 kΩ, A_V = 1, f = 1 kHz		0.003		%
EMI Rejection of +IN x	EMIR	V_{IN} = 200 mV p-p				
f = 1000 MHz				70		dB
f = 2400 MHz				90		dB
NOISE PERFORMANCE						
Voltage Noise	$e_{n\ p-p}$	0.1 Hz to 10 Hz		175		nV p-p
Voltage Noise Density	e_n	f = 10 Hz		10		nV/√Hz
		f = 1 kHz		8		nV/√Hz
Current Noise Density	i_n	f = 1 kHz		0.2		pA/√Hz

[1] All inputs are stressed to 32 V beyond supplies for 500 ms.

ELECTRICAL CHARACTERISTICS, ±15 V

V_{SY} = ±15 V, V_{CM} = 0 V, T_A = 25°C, unless otherwise noted.

Table 2.

Parameter	Symbol	Test Conditions/Comments	Min	Typ	Max	Unit
INPUT CHARACTERISTICS						
Offset Voltage	V_{OS}			3	120	µV
Offset Voltage Matching					110	µV
Input Bias Current	I_B		−1	−0.3	+1	nA
Input Offset Current	I_{OS}		−0.75	+0.1	+0.75	nA
Input Voltage Range	IVR		−13.5		+13.5	V
Overvoltage Current Limit[1]	I_{OVP}	15 V < V_{CM} < 47 V		12		mA
		−47 V < V_{CM} < −15 V		10		mA
Common-Mode Rejection Ratio	CMRR	−13.5 V ≤ V_{CM} ≤ +13.5 V	128	130		dB
Large Signal Voltage Gain	A_{VO}	R_L = 2 kΩ, V_{OUT} = −14.2 V to +14.2 V	110	114		dB
		R_L = 10 kΩ, V_{OUT} = −14.5 V to +14.5 V	118	120		dB
Input Capacitance	C_{INDM}	Differential mode		1		pF
	C_{INCM}	Common mode		8		pF
Input Resistance	R_{DIFF}	Differential mode		4		MΩ
	R_{CM}	Common mode		130		GΩ
OUTPUT CHARACTERISTICS						
Output Voltage						
High	V_{OH}	I_{LOAD} = 1 mA	14.95			V
		I_{LOAD} = 7 mA	14.80			V
Low	V_{OL}	I_{LOAD} = 1 mA			−14.95	V
		I_{LOAD} = 7 mA			−14.80	V
Output Current	I_{OUT}	$V_{DROPOUT}$ < 1 V		25		mA
Short-Circuit Current	I_{SC}	T_A = 25°C				
Sourcing				53		mA
Sinking				65		mA
Closed-Loop Output Impedance	Z_{OUT}	f = 1 kHz, A_V = 1		0.08		Ω
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	V_{SY} = ±2.5 V to ±18 V	125	145		dB
Supply Current per Amplifier	I_{SY}	V_{OUT} = 0 V		500	580	µA
DYNAMIC PERFORMANCE						
Slew Rate	SR	R_L = 2 kΩ		1.5		V/µs
Settling Time	t_S					
To 0.1%		V_{IN} = 10 V p-p, R_L = 2 kΩ, A_V = −1		5.5		µs
To 0.01%		V_{IN} = 10 V p-p, R_L = 2 kΩ, A_V = −1		7.5		µs
Gain Bandwidth Product	GBP	V_{IN} = 10 mV p-p, R_L = 2 kΩ, A_V = 100		3.5		MHz
Unity-Gain Crossover	UGC	V_{IN} = 10 mV p-p, R_L = 2 kΩ, A_V = 1		3.5		MHz
−3 dB Closed-Loop Bandwidth	$f_{−3 dB}$	V_{IN} = 10 mV p-p, R_L = 2 kΩ, A_V = 1		6		MHz
Total Harmonic Distortion Plus Noise	THD + N	V_{IN} = 1 V rms, A_V = 1, R_L = 2 kΩ, f = 1 kHz		0.002		%
EMI Rejection of +IN x	EMIR	V_{IN} = 200 mV p-p				
f = 1000 MHz				70		dB
f = 2400 MHz				90		dB
NOISE PERFORMANCE						
Voltage Noise	$e_{n\ p\text{-}p}$	0.1 Hz to 10 Hz		175		nV p-p
Voltage Noise Density	e_n	f = 10 Hz		10		nV/√Hz
		f = 1 kHz		8		nV/√Hz
Current Noise Density	i_n	f = 1 kHz		0.2		pA/√Hz
MULTIPLE AMPLIFIERS, CHANNEL SEPARATION	C_S	f = 1 kHz		127		dB

[1] All inputs are stressed to 32 V beyond supplies for 500 ms.

ABSOLUTE MAXIMUM RATINGS

Table 3.

Parameter	Rating
Supply Voltage	36 V
Input Voltage	$V_{SY} \pm 32$ V
Differential Input Voltage	$\pm V_{SY}$
Storage Temperature Range	−65°C to +150°C
Operating Temperature Range	−40°C to +125°C
Junction Temperature Range	−65°C to +150°C

Stresses at or above those listed under Absolute Maximum Ratings may cause permanent damage to the product. This is a stress rating only; functional operation of the product at these or any other conditions above those indicated in the operational section of this specification is not implied. Operation beyond the maximum operating conditions for extended periods may affect product reliability.

ELECTROSTATIC DISCHARGE (ESD) RATINGS

The following ESD information is provided for handling of ESD sensitive devices in an ESD protected area only.

Human body model (HBM) per ANSI/ESDA/JEDEC JS-001. Field induced charged device model (FICDM) per ANSI/ESDA/JEDEC JS-002.

Machine model (MM) per ANSI/ESD STM5.2. MM voltage values are for characterization only.

ESD Ratings for ADA4177-2CHIPS

Table 4. ADA4177-2CHIPS, 8-Pad CHIP

ESD Model	Withstand Threshold (V)	Class
HBM	4000	3A
FICDM	1250	IV
MM	200	Not applicable

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Charged devices and circuit boards can discharge without detection. Although this product features patented or proprietary protection circuitry, damage may occur on devices subjected to high energy ESD. Therefore, proper ESD precautions should be taken to avoid performance degradation or loss of functionality.
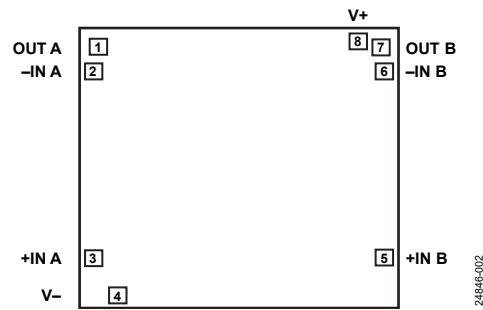
PIN CONFIGURATION AND FUNCTION DESCRIPTION

Figure 2. Pad Configuration

Table 5. Pad Configuration Descriptions[1]

Pad No.	Mnemonic	X Coordinate	Y Coordinate	Description
1	OUT A	−600	+522	Output, Channel A
2	−IN A	−625	+421	Inverting Input, Channel A
3	+IN A	−625	−389	Noninverting Input, Channel A
4	V−	−520	−550	Negative Supply Voltage
5	+IN B	+625	−389	Noninverting Input, Channel B
6	−IN B	+625	+421	Inverting Input, Channel B
7	OUT B	+600	+522	Output, Channel B
8	V+	+510	+550	Positive Supply Voltage

[1] All dimensions are referenced from the center of the die to the center of each bond pad.
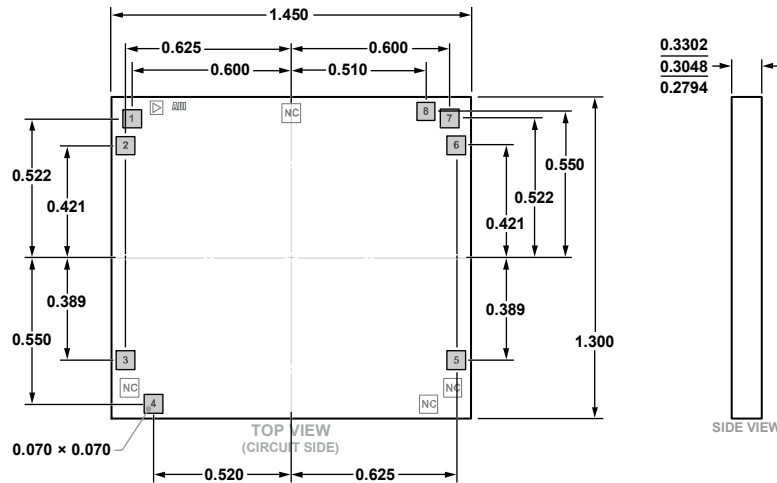
OUTLINE DIMENSIONS

Figure 3. 8-Pad Bare Die [CHIP]
(C-8-24))
Dimensions shown in millimeters

DIE SPECIFICATIONS AND ASSEMBLY RECOMMENDATIONS

Table 6. Die Specifications

Parameter	Value	Unit
Chip Size	1360 × 1210	µm
Scribe Line Width	90	µm
Die Size (Maximum)	1450 × 1300	µm
Thickness	12	mils
Backside	Connect to V−	Not applicable
Passivation	Undoped oxide/silicon nitride (SiN)	Not applicable
Bond Pads (Minimum)	70 × 70	µm
Bond Pad Composition	Aluminum silicon (AlSi) (1.0%), copper (Cu) (0.5%)	%
Polyimide Thickness	18	µm
Die Marker ID	ada4177_2z	Not applicable

Table 7. Assembly Recommendations

Assembly Component	Recommendation
Die Attach	Hitachi EN 4900GC
Bonding Method	Forward bond
Bonding Sequence	Lead to bond first = 1

ORDERING GUIDE

Model[1]	Temperature Range	Package Description	Package Option	Ordering Quantity
ADA4177-2CHIPS	−40°C to +125°C	8-Pad Bare Die [CHIP]	C-8-24	400

[1] ADA4177-2CHIPS is RoHS compliant.

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